

FEB2 “Slice” Testboard Update

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NEVIS LABORATORIES
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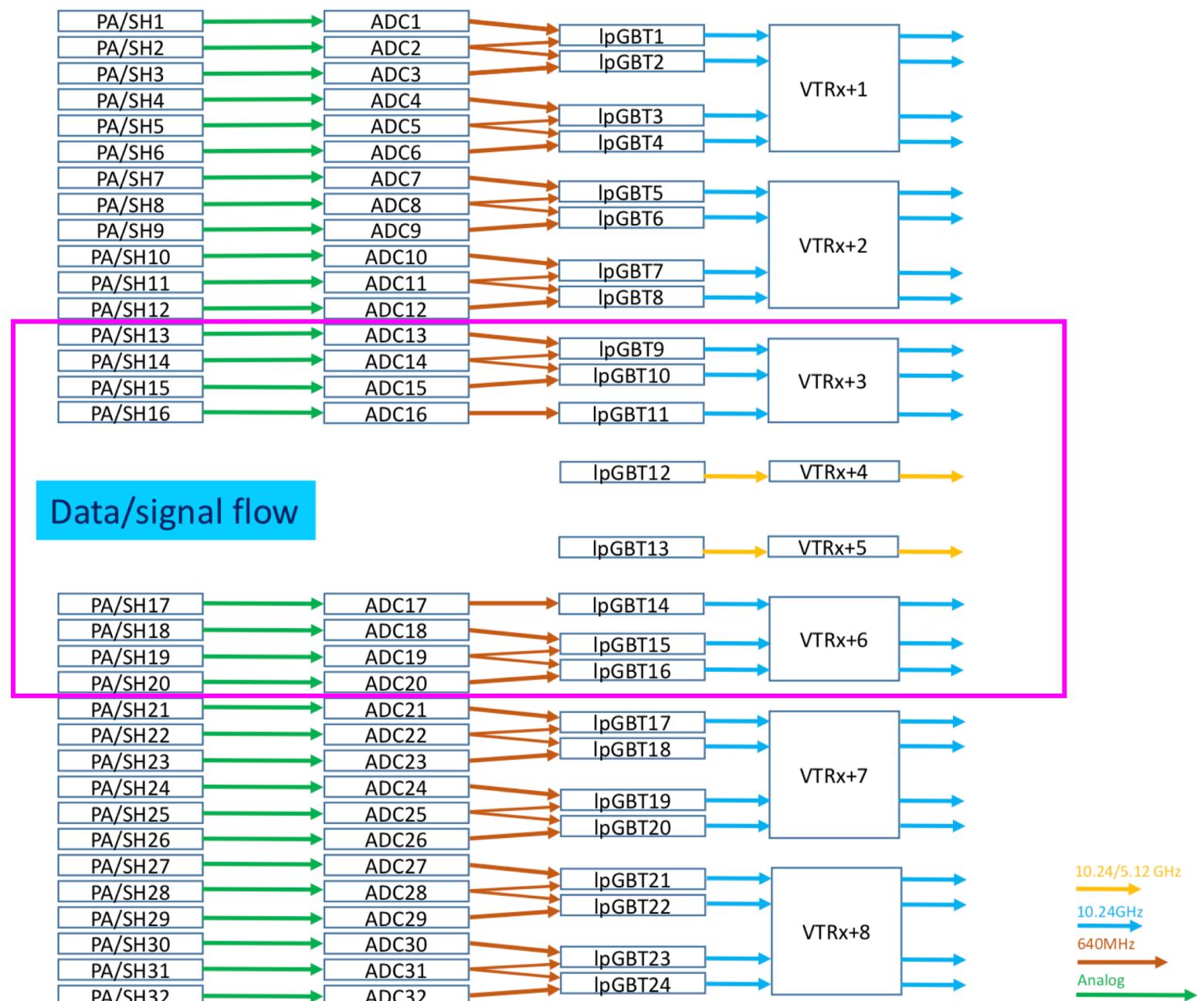


Overview

- Analog Testboard (2019)
 - 2 (LAUROC1 PA/S + COLUTAv2 ADC) + IpGBT
 - Verified full readout chain PA/S + ADC + optical data links
- **Slice Testboard (2020-2021)**
 - 8 (LAUROC2 PA/S + COLUTAv3 ADC + IpGBT) chips, 32 LAr channels available
 - Aim to demonstrate multichannel performance, bi-directional control links
 - v1.1 of the board is being tested at Nevis now – first fully assembled version after debugging done on partially assembled v1.0 board
- Full FEB2 Prototype (2021-2022)
 - All 128 channels

Review: FEB2 Data/Signal Flow

- V1.1 board assembled with full set of 8 PA/S, 8 ADCs, 8 IpGBTs
 - up from only 2 PA/S & 3 ADC on v1.0
- 32 channels of readout
 - Each channel represents a HI/LO gain pair
- Results will be shown only for the 16 MDAC channels



Features of v1.1

- New optical connections, designed by SMU
 - Front panel mounted connectors
- Fix for the IpGBT 12 & IpGBT13 master problem
 - The first time the board is brought up, we need to communicate with IpGBT12&13 to burn e-fuses
 - On v1.0, we had to cut the M2 lines to allow this communication
 - On v1.1, we can now isolate undefined IpGBT12&13 masters by changing the headers on the board
 - As soon as I2C buses are free we burn e-fuses on IpGBT12&13, and IpGBT11&14
 - This is a one time operation – once done the board can be fully operated via FELIX



Status of the v1.1 boards

Both boards are fully operational!

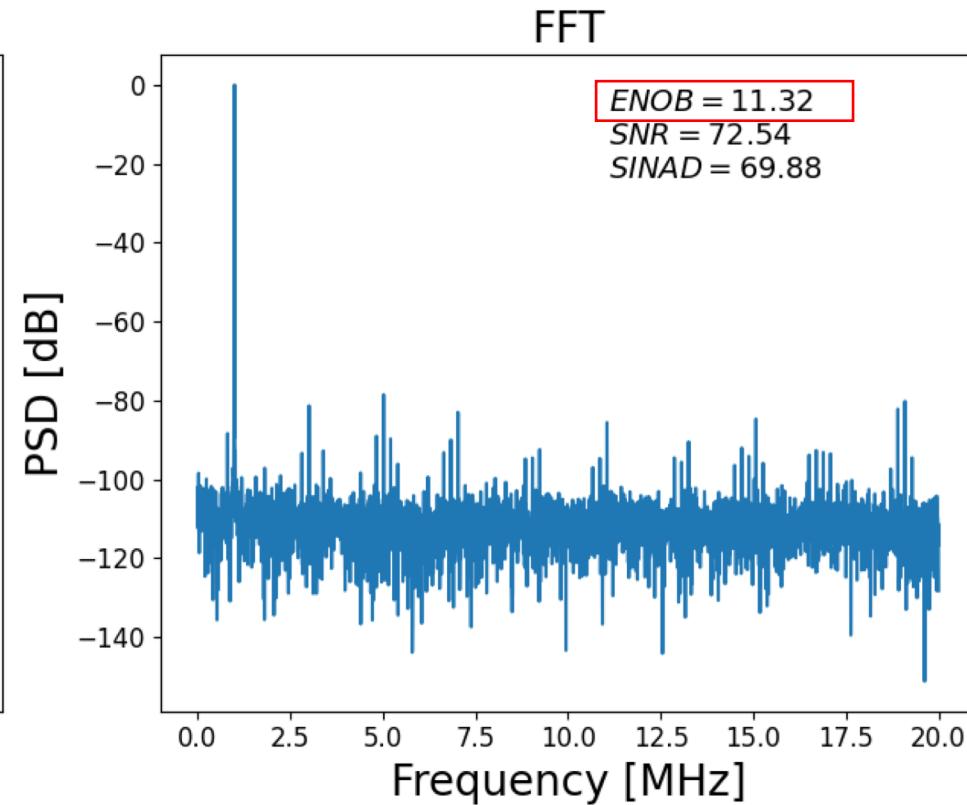
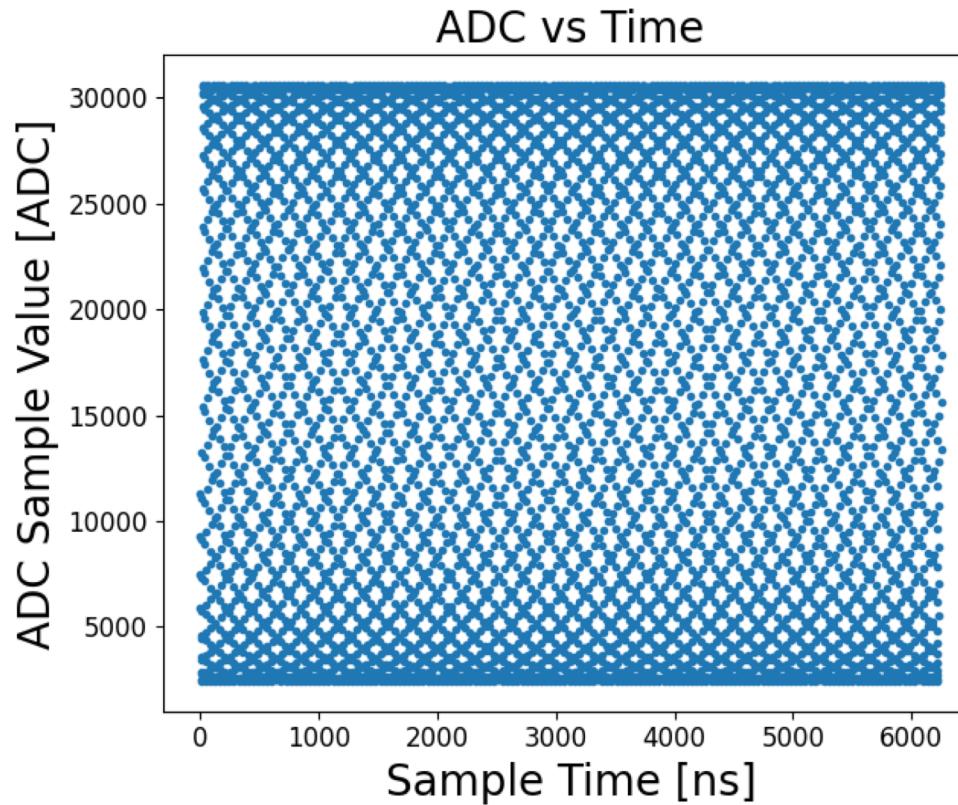
- ✓ Bi-directional I2C control established between each master IpGBT (12/13) and all secondary chips (4 PA/S, 4 ADCs, 3 data IpGBTs for each master IpGBT)
- ✓ Correct clock parameters have been determined for each ADC/IpGBT pair
 - Clock synchronization parameters must be tuned for each ADC/IpGBT pair independently on every board
- ✓ We have seen correct test pattern data + noise data on all 32 channels
- ✓ We have measured a sine wave signal through ADC20, which has a test input for this purpose

Voltage and Temperature Monitoring

- We have implemented in our DAQ GUI a fully software-based system for monitoring the voltage of all test points
 - We have a similar system for monitoring the temperature

Control	Voltages	Temperature													
	Name	Measured Value	Nominal Value	Name	Measured Value	Nominal Value	Name	Measured Value	Nominal Value	Name	Measured Value	Nominal Value	Name	Measured Value	Nominal Value
LpGBT9	<input checked="" type="checkbox"/> PA9-16 +2.5V	2.32	+2.5V	<input checked="" type="checkbox"/> PA9-16 +1.2V	1.15	+1.2V									
LpGBT10	<input checked="" type="checkbox"/> ADC13 VDD	1.16	+1.2V	<input checked="" type="checkbox"/> ADC14 VDD	1.16	+1.2V	<input checked="" type="checkbox"/> ADC15 VDD	1.16	+1.2V	<input checked="" type="checkbox"/> VTRX3 1P2	1.16	+1.2V			
LpGBT11	<input checked="" type="checkbox"/> ADC16 VDD	1.10	+1.2V	<input checked="" type="checkbox"/> REF VDD	1.11		<input checked="" type="checkbox"/> VTRX3 RSSI	2.26		<input checked="" type="checkbox"/> VTRX4 1P2	1.10	+1.2V			
LpGBT12	<input checked="" type="checkbox"/> V2.5 MON A	2.31	+2.5V	<input checked="" type="checkbox"/> VTRX4 RSSI	0.53								Read Voltages		
LpGBT13	<input checked="" type="checkbox"/> V2.5 MON B	2.34	+2.5V	<input checked="" type="checkbox"/> VTRX5 RSSI	0.50								Display ADC Counts		
LpGBT14	<input checked="" type="checkbox"/> ADC17 VDD	1.15	+1.2V	<input checked="" type="checkbox"/> VTRX5 1P2	1.14	+1.2V	<input checked="" type="checkbox"/> VTRX6 1P2	1.15	+1.2V				Select All Voltages		
LpGBT15	<input checked="" type="checkbox"/> PA17-24 +2.5V	2.35	+2.5V	<input checked="" type="checkbox"/> PA17-24 +1.2V	1.14	+1.2V	<input checked="" type="checkbox"/> VTRX6 RSSI	2.36					Unselect All Voltages		
LpGBT16	<input checked="" type="checkbox"/> ADC18 VDD	1.16	+1.2V	<input checked="" type="checkbox"/> ADC19 VDD	1.15	+1.2V	<input checked="" type="checkbox"/> ADC20 VDD	1.15	+1.2V	<input checked="" type="checkbox"/> MAIN PS	1.13				

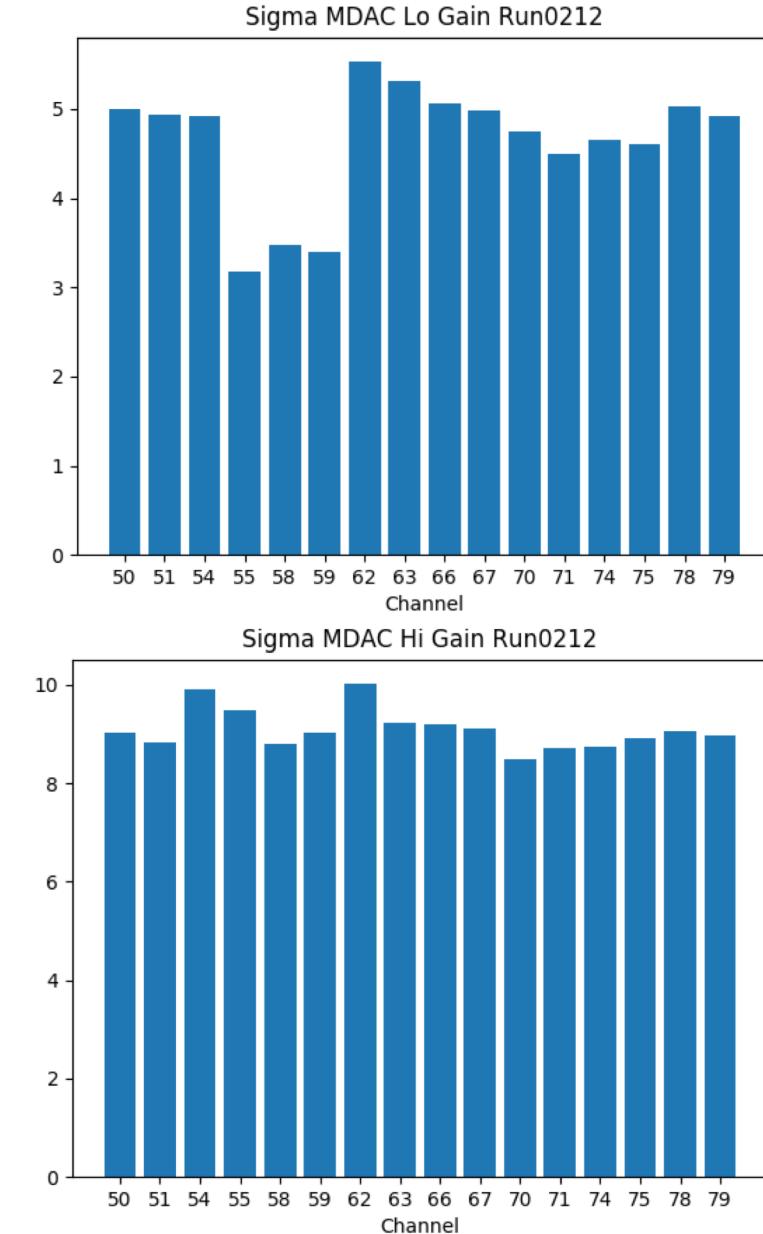
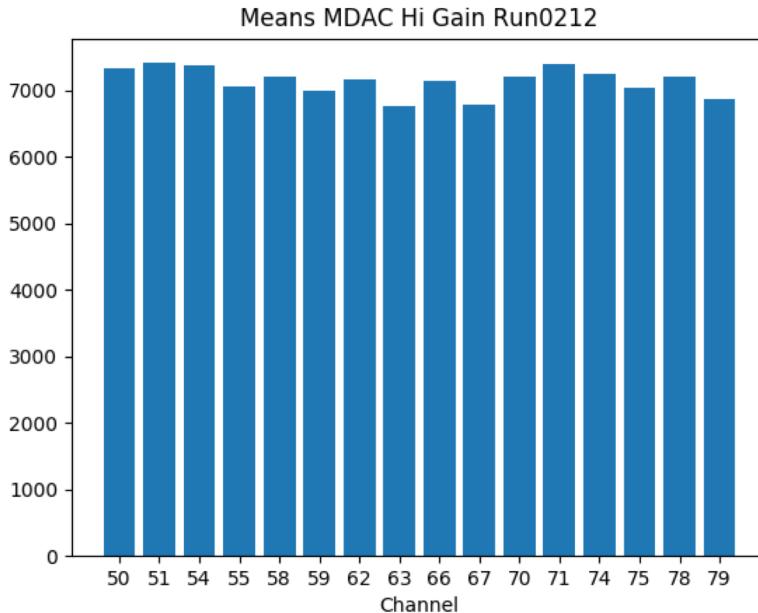
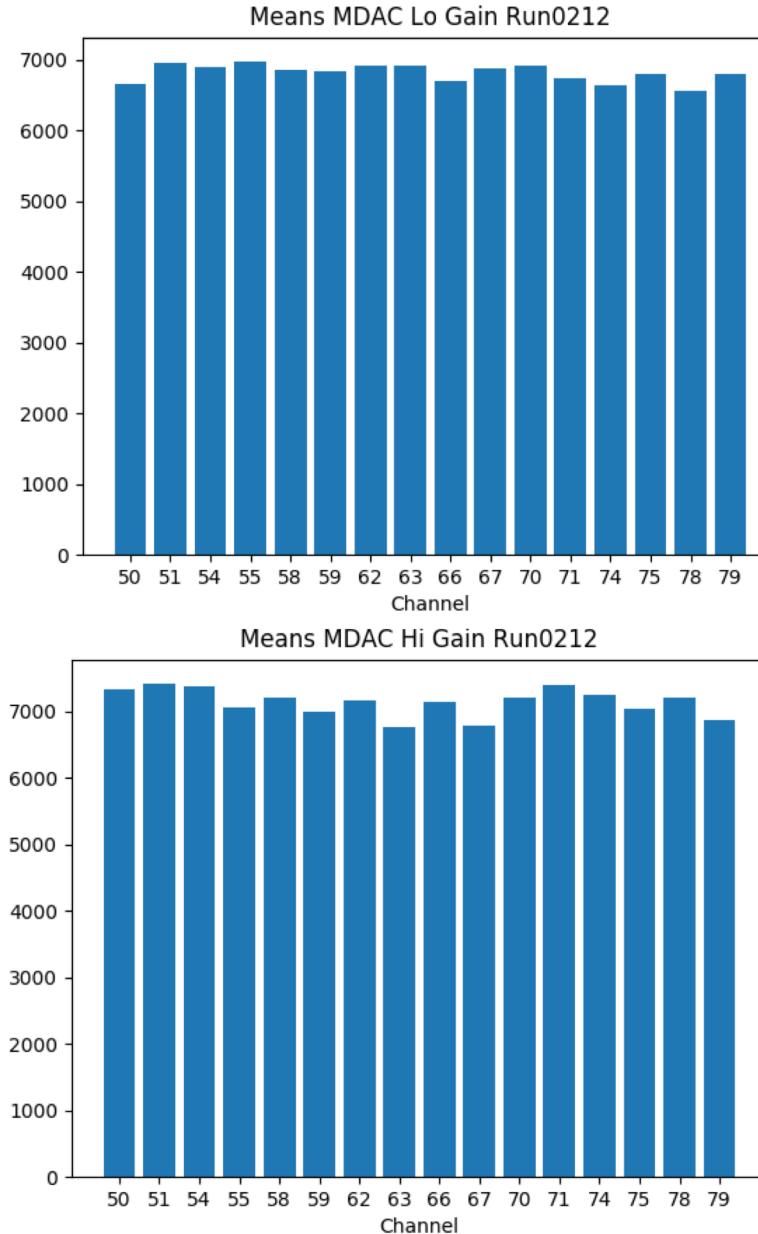
Sine Wave Results



* Spikes in the FFT are most likely due to the MDAC transition sample offset which is an understood problem – there is a solution planned for CV4

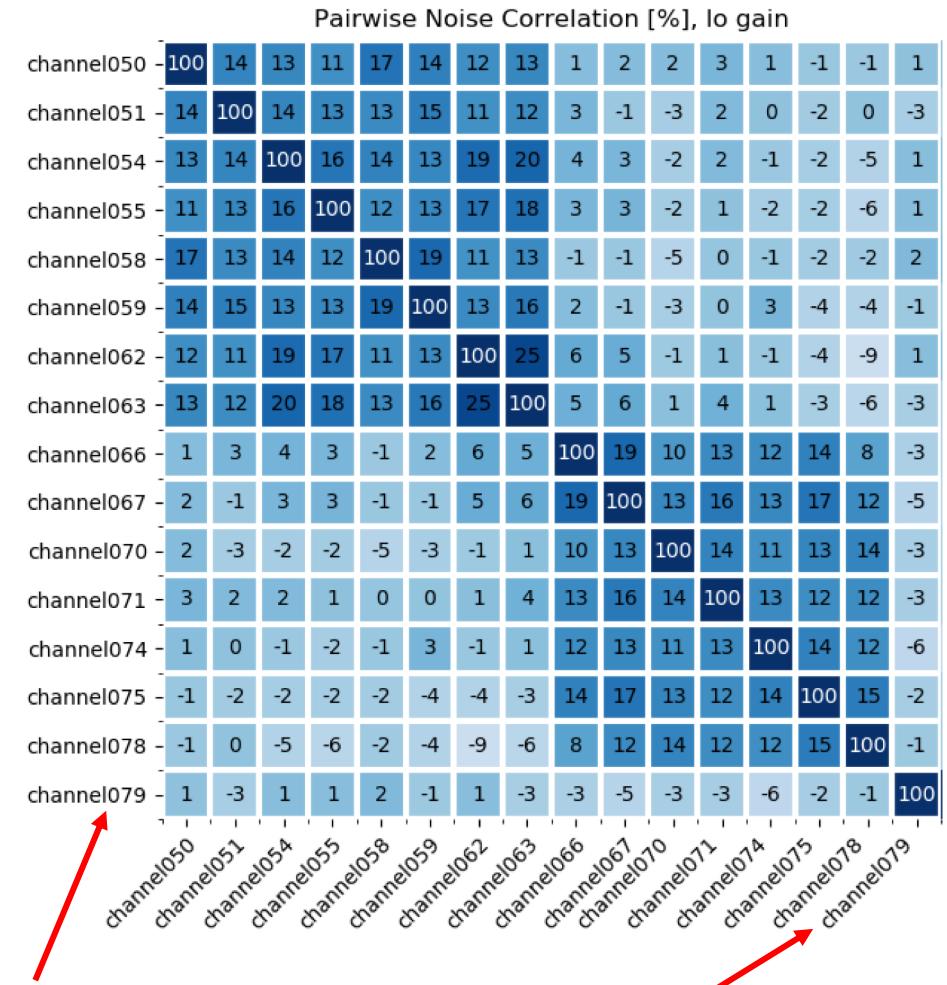
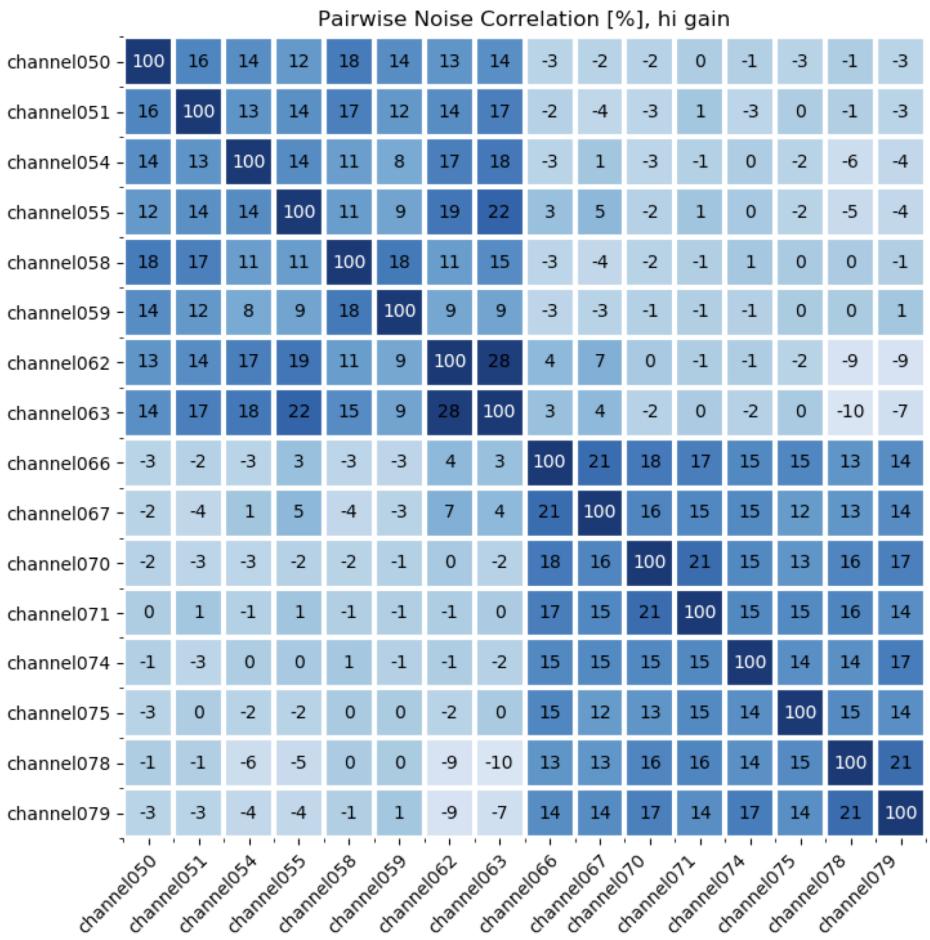
Noise Results

- Summary of noise results with the default PA/S parameters
 - The baselines have been adjusted so that all channels have a baseline close to 7000 counts
- On average we see ~ 9 counts of noise in the HG, and ~ 5 counts of noise in the LG
- These noise levels are higher than expected



Noise Correlation

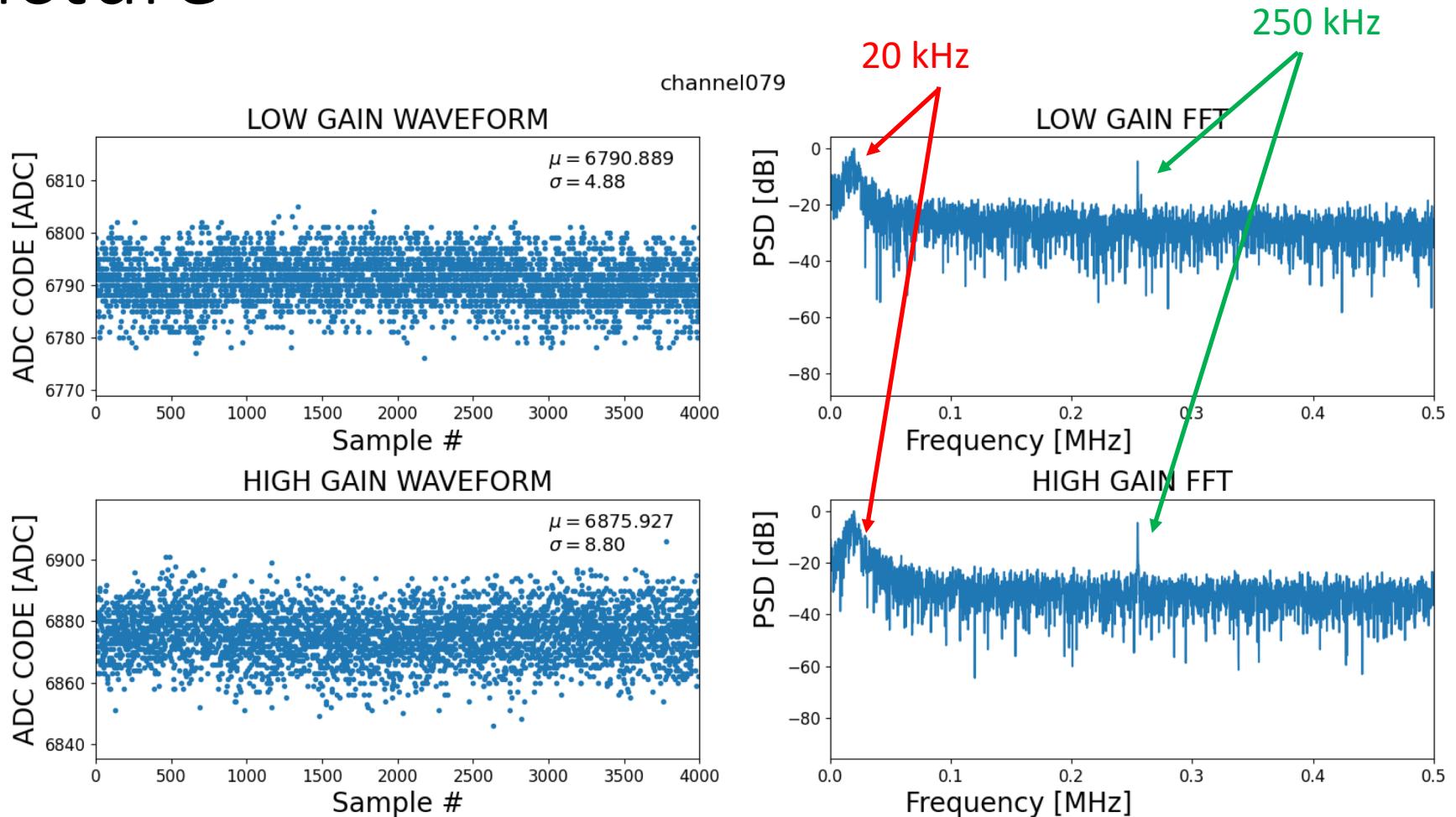
- Noise is correlated within each half of the board
- Within a half of the board, the noise correlation is mostly flat, and large (~10-20%)
- Opposite sides of the board are slightly negatively correlated



* Ch79 LG is disconnected from the PA/S

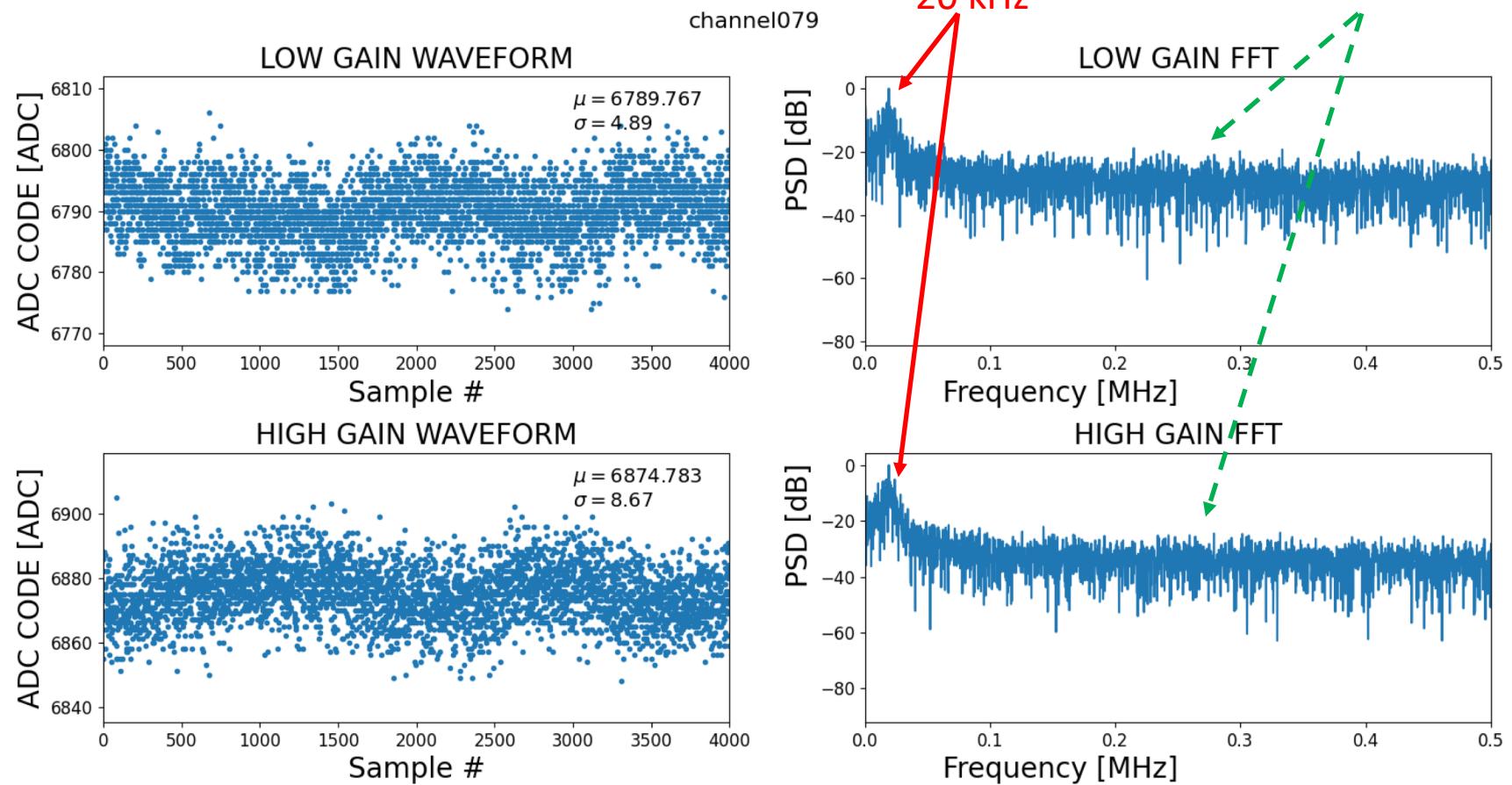
Noise Structure

- There is a prominent 250 kHz spike in the FFT of the pedestal data
- We also observe a broad peak around 20 kHz
- The DCDC converters operate at 250 kHz – we wanted to isolate them as the source of the 250 kHz spike



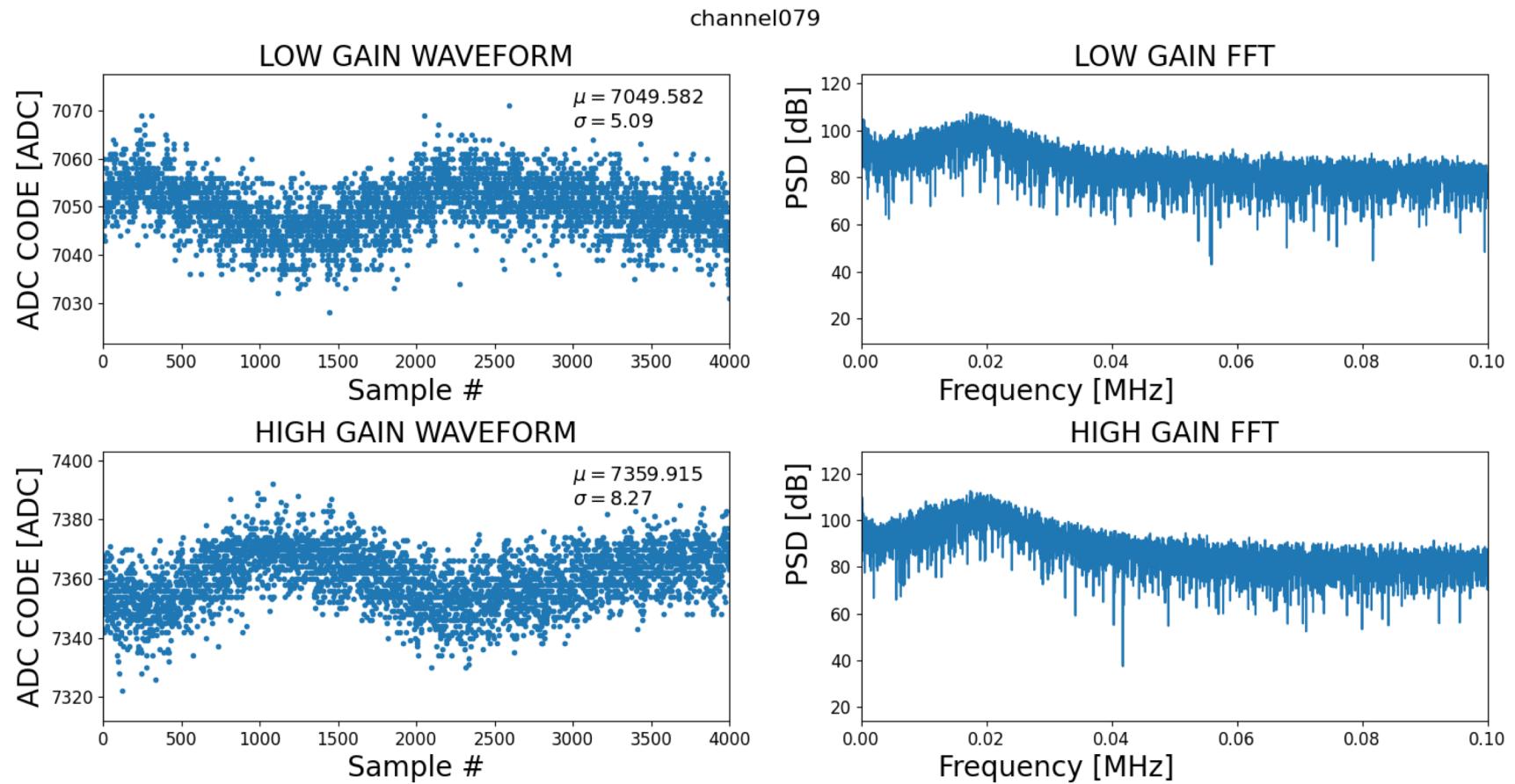
Noise with External Linear Power Supply

- For this measurement we bypass the DCDC converters with linear external power supplies
- We see the 250 kHz spike disappears, but the large peak around 20 kHz remains



20 kHz Noise

- We see the 20kHz noise is very dominant in the noise distribution
- We would like to understand where the noise comes from, and how it couples to our measurements



Investigating 20 kHz Noise

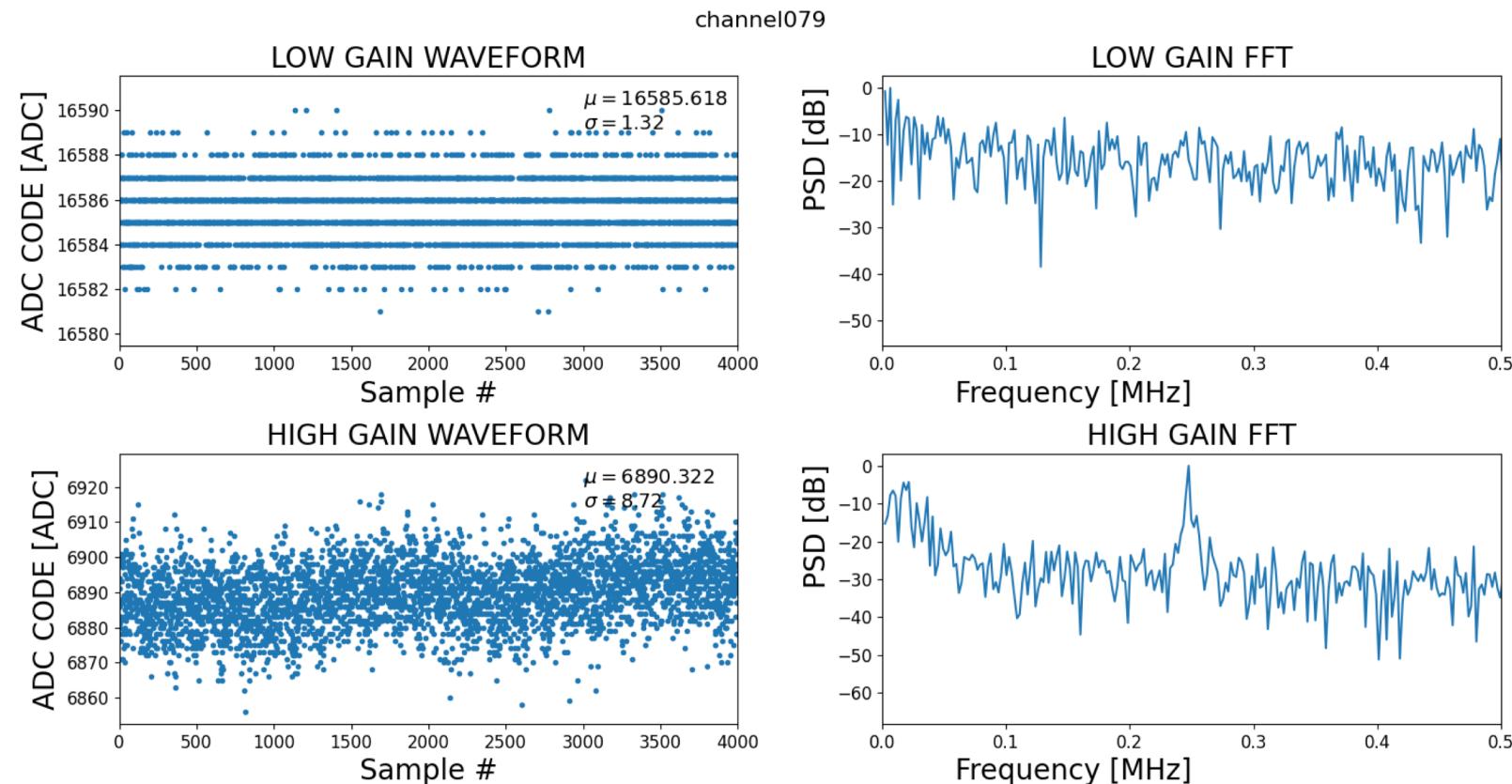
We have so far tried a number of modifications to the board to see if we could isolate the source of the 20 kHz noise:

- Adding a Faraday cage over the input connectors
- Adding a Faraday cage over the preamps
- Shorting the signal input pins
- Disabling the PA/S 40 MHz clock
- Removing the AC-coupling capacitor in the input protection networks, in order to disconnect the PA/S input
- Partially disabling the preamp
 - `ON_pa=0, ON_g20=1, ON_lg_s1=1, ON_hg_S1=1, ON_lg_s2=1, ON_hg_s2=1`
 - `ON_pa=0, ON_g20=0, ON_lg_s1=1, ON_hg_s1=1, ON_lg_s2=1, ON_hg_s2=1`
 - `ON_pa=0, ON_g20=0, ON_lg_s1=0, ON_hg_s1=0, ON_lg_s2=1, ON_hg_s2=1`

The 20kHz noise remained roughly consistent through all these tests

Ch79 LG - Disconnected from PA/S

- Ch79 LG can be disconnected from the PA/S
 - This was done we so we can send an external pulse to the chip
- We see the 20 kHz noise is gone in this measurement, and the noise is greatly reduced (1.3 counts, down from 4.9 counts)
- This, coupled with our other tests, implies 20 kHz noise is coming through the PA/S



Timeline (updates since Dec LAr Week Presentation)

- ✓ Dec 28 - Received new PCBs and submitted for assembly
- ✓ ~~Jan 25~~ Feb 15 - Began testing of 2 new fully assembled boards
- ? Mar 5 – New PA/S chips sent from Omega for packaging

Next Steps

- We are working to uncover the reason for the high noise levels and come up with a solution
- We can submit 3 more boards to the assembler once we have the new PA/S chips

Conclusions

- We have demonstrated control and readout of all 32 channels on both fully assembled v1.1 Slice Testboards
- Up to 3 more boards can be produced once more PA/S chips are available
- We have begun performance evaluation of the board and will continue in the coming weeks
 - Investigations of the noise performance continue

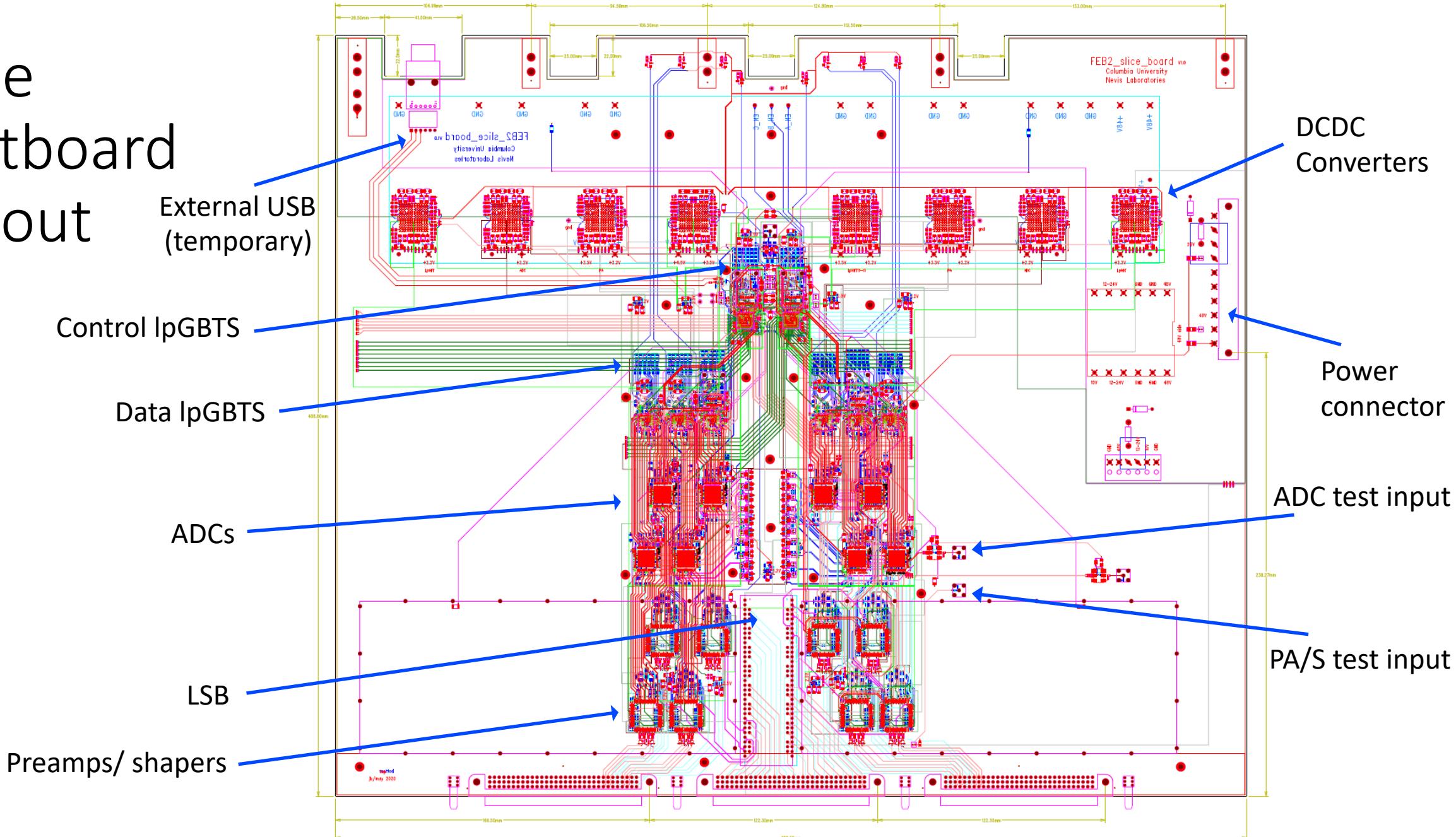
Backup



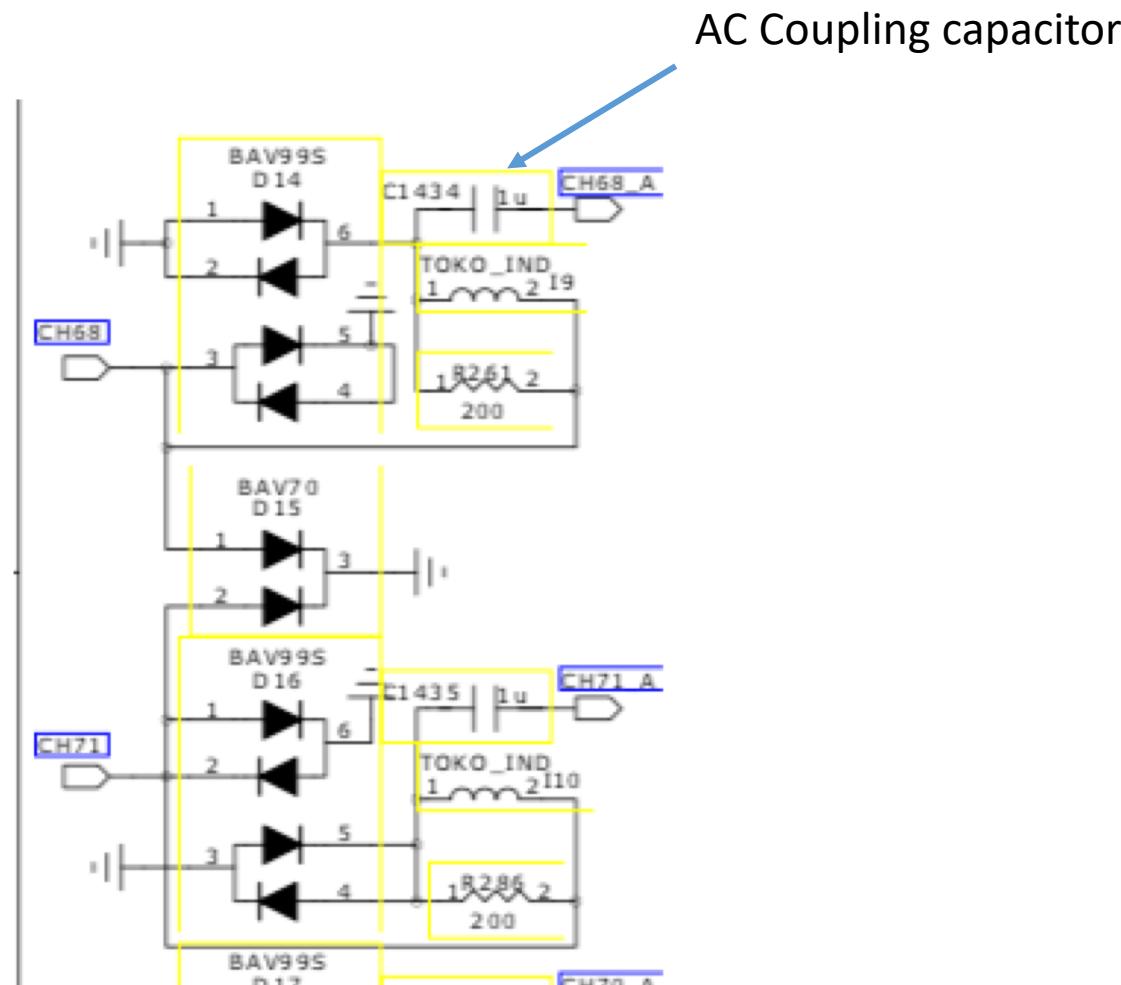
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Slice Testboard Layout

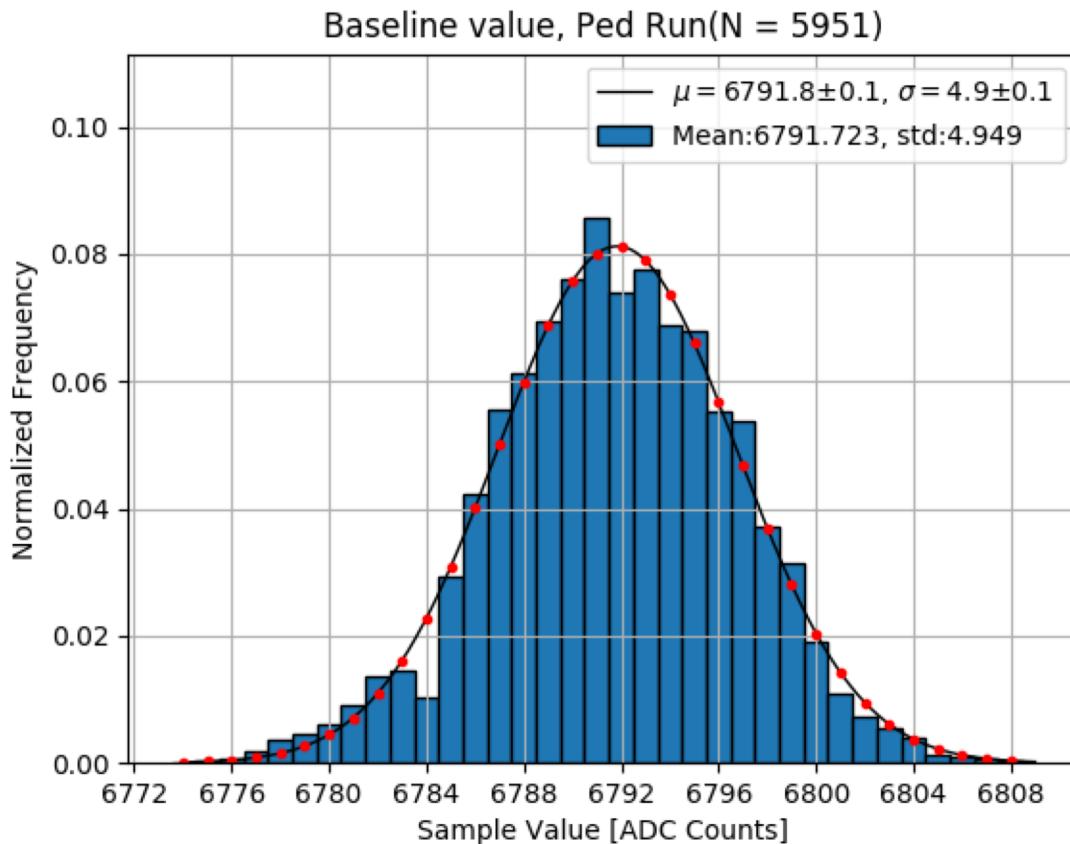


PA/S Schematic

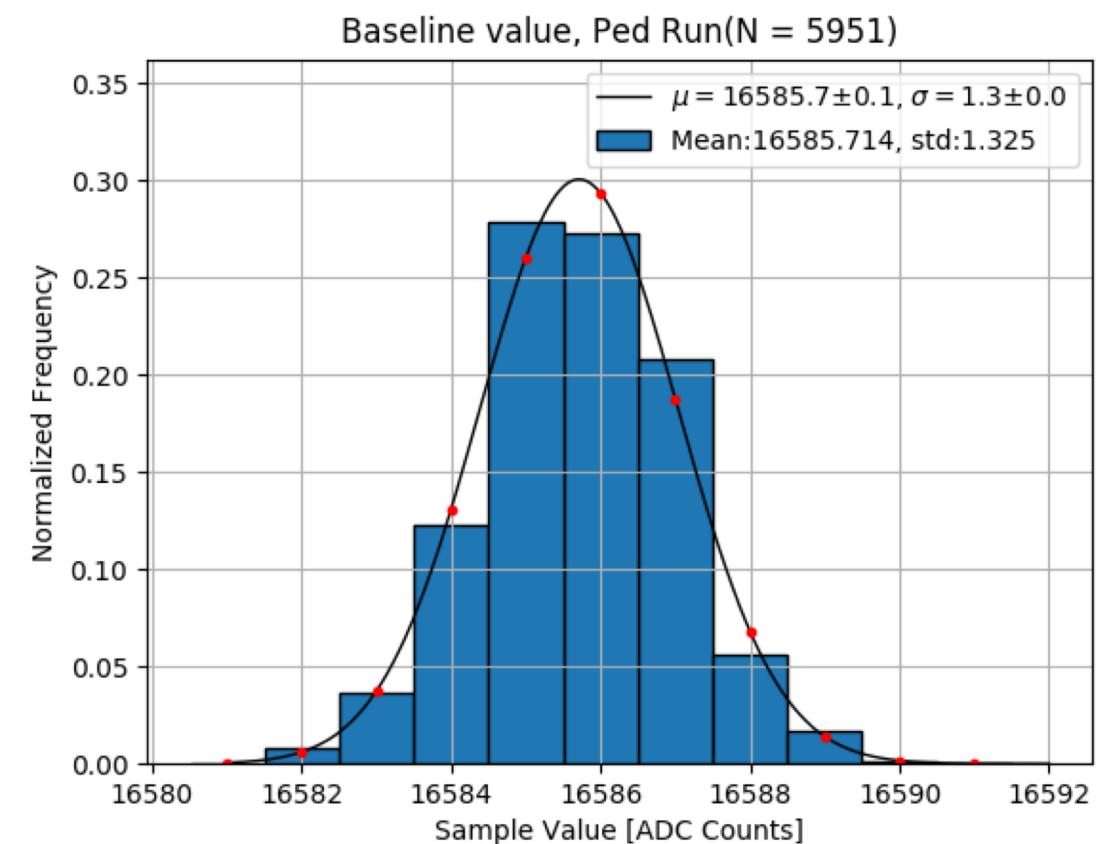


Ch79 LG Noise Histograms

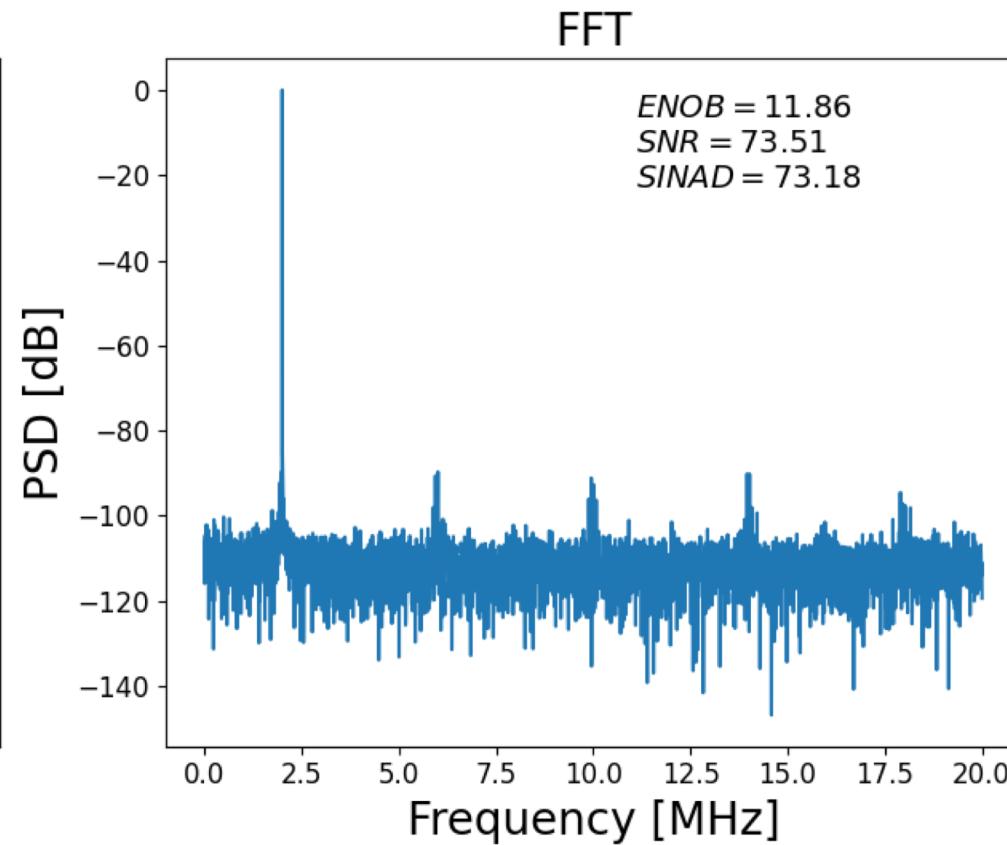
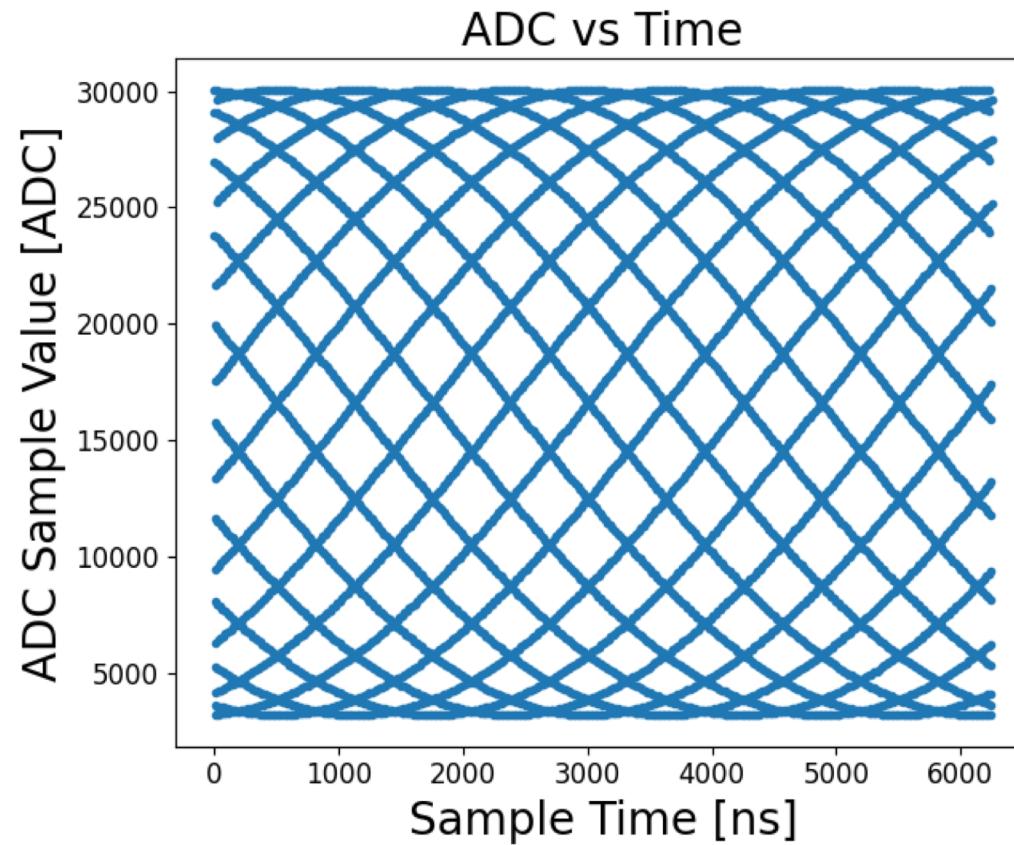
Connected to PA/S



Disconnected from PA/S



Sine Wave Results from v1.0



Noise Results from v1.0

Channels 66 & 67 are not connected to a LAUROC (no LAUROC17 on board)

